

## **Search Notes**



**Application/Control No.**

10/644,782

---

**Examiner**

John P. Sheehan

**Applicant(s)/Patent under  
Reexamination**

KANEKO ET AL.

## **Art Unit**

1742

**SEARCHED**

## **SEARCH NOTES (INCLUDING SEARCH STRATEGY)**

## **INTERFERENCE SEARCHED**

# INTERFERENCE SEARCHED